

**Qualification Results Summary of 24-LGA_CAV
Package at STATS ChipPAC Korea**

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3 x 77	Pass
Temperature Humidity Bias (THB)*	JEDEC <i>JESD22-A101</i>	3 x 77	Pass
Temperature Humidity Dwell (THD)*	JEDEC <i>JESD22-A101</i>	3 x 77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1 x 45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3 x 11	Pass
Latch-Up	JEDEC <i>JESD78</i>	3/stress	Pass +/- 200mA
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass +/-3000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	ESDA/JEDEC <i>JS-002</i>	3/voltage	Pass +/-1250V

* These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: 1. Bake – 2 hours at 125°C; 2. Soak – unbiased soak for 192 hours at 30°C, 60%RH; 3. Reflow – three passes through a reflow oven with a peak temperature of 260°C.